

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): MAMITSU et al.	Atty. Dkt.: 01-103-CON2
Serial No.: Unknown	Group Art Unit:
Filed: Concurrently herewith	Examiner:
Title: SEMICONDUCTOR DEVICE HAVING RADIATION STRUCTURE	

Commissioner for Patents  
Arlington, VA 22202

Date: November 4, 2003

**INFORMATION DISCLOSURE STATEMENT**

Sir:

Pursuant to 37 C.F.R. §1.56, the reference(s) listed on the attached Form PTO-1449 is/are being submitted for consideration by the Examiner without any admission that it/they constitute(s) statutory prior art, or without any admission that it/they contain(s) subject matter that anticipates the invention or renders the invention obvious to a person of ordinary skill in the art.

The Examiner is requested to initial the attached PTO Form-1449 and to return a copy of same to the undersigned attorney as proof that the listed reference(s) has/have been considered and made of record.

Respectfully submitted,



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FORM PTO-1449	ATTY. DKT NO.	1-103-CON2	SER. NO.
	APPLICANT	MAMITSU et al.	
	FILING DATE	Nov. 04, 2003	GROUP

REFERENCE DESIGNATION

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
		5,990,550	Nov. 23, 1999	Umezawa		
		5,608,610	Mar. 4, 1997	Brzezinski		
		5,396,403	Mar. 7, 1995	Patel		
		5,293,301	Mar. 8, 1994	Tanaka et al.		
		5,641,997	June 24, 1997	Ohta et al.		
		5,789,820	Aug. 4, 1998	Yamashita		

FOREIGN PATENT DOCUMENTS

TRANSLATION

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
		60-235430	11/85	JAPAN					
		07-240432	9/95	JAPAN					
		8-45874	2/96	JAPAN					
		60-95947	05/85	JAPAN					
		61-265849	11/86	JAPAN					
		62-141751	06/87	JAPAN					
		63-096946	04/88	JAPAN					
		62-92349	4/87	JAPAN					
		62-287649	12/87	JAPAN					
		59-38734	09/84	JAPAN					
		01-228138	09/89	JAPAN					
		54-40569	03/79	JAPAN					
		61-251043	11/86	JAPAN					
		54-95183	07/79	JAPAN					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER		DATE CONSIDERED

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
		2002/0158333	Oct. 31, 2002	Teshima		
		S/N 10/201556	July 24, 2002	Hirano et al.		
		5726466	March 10, 1998	Nishitani		
		4,470,063	Sep. 4, 1984	Arakawa et al.		
		5,708,299	Jan. 13, 1998	Teramae et al		

FOREIGN PATENT DOCUMENTS

TRANSLATION

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
		59-031042	02/84	JAPAN					
		07-038013	02/95	JAPAN					
		07-273276	10/95	JAPAN					
		08-191145	07/96	JAPAN					
		2000-91485	03/00	JAPAN					
		W098/12748	3/26/98	PCT					
		JP-A-5-283562 *	10/29/93	JAPAN				X	
		JP-A-6-349987 *	12/22/94	JAPAN				X	
		JP-A-7-45765 *	2/14/95	JAPAN				X	
		JP-A-11-186469 *	7/9/99	JAPAN				X	
		JP-A-2000-31351 *	1/28/00	JAPAN				X	
		JP-A-2001-118961 *	4/27/01	JAPAN				X	

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

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EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
		5,708,299	Jan. 13, 1998	Teramae et al		
		6,072,240	June 6, 2000	Kimura et al		
		5,248,853	Sep. 28, 1993	Ishikawa et al		
		5,801,445	Sep. 1, 1998	Ishihara et al		
		5,229,646	Jul. 20, 1993	Tsumura		
		4,558,345	Dec. 10, 1985	Dwyer et al		
		4,546,374	Oct. 8, 1985	Olsen et al		
		4,984,061	Jan. 8, 1991	Matsumoto		
		5,481,137	Jan 2, 1996	Harada et al.		
		4,827,082	May 2, 1989	Horiuchi et al		
		4,538,170	Aug. 27, 1985	Yerman		

FOREIGN PATENT DOCUMENTS

TRANSLATION

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
		EP0660396	12/24/93	Europe					
		EP0450980	4/05/91	Europe					
		6-291223	10/94	JAPAN					
		3-20067	01/91	JAPAN					
		2146174	11/85	GB					

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

		Takamura, "Electronic Technology", pp. 56-59 (1999-5).
		Johnson et al., "Silicon Precipitate Nodule-Induced Failures of MOSFETS", ISTFA '91 (Nov. 11-15, 1991), pp. 161-165.
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## U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
	4,646,129	Feb. 24, 1987	Yerman et al		
	4,141,030	Feb. 20, 1979	Eisele et al		
	6,448,645	Sep. 10, 2002	Kimura		
	6,538,308	Mar. 25, 2003	Nakase		
	6,380,622	Apr. 30, 2002	Hirai		
	09/675,209	Filed Sept. 29, 2000	Suzuki		
	5,221,851	Jun. 22, 1993	Gobrecht et al.		

## FOREIGN PATENT DOCUMENTS

## TRANSLATION

	DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
	4-249353	9/92	JAPAN					
	11-260979	09/99	JAPAN					
	4-27145	01/92	JAPAN					
	9-148492	06/97	JAPAN					
	4-12555	01/92	JAPAN					
	4-103150	04/92	JAPAN					
	60-137042	07/85	JAPAN					
	5-109919	04/93	JAPAN					
	61-166051	07/86	JAPAN					
	2-117157	05/90	JAPAN					
	63-102326	05/88	JAPAN					

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

EXAMINER		DATE CONSIDERED